Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination

1652

10/031,146 HAUER ET AL.

Examiner Art Unit

YONG D. PAK

SEARCHED					
Class	Subclass	Date	Examiner		

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
435	189	1/25/2011	ΥP		
435	440	1/25/2011	YP		
435	132	1/25/2011	YP		
stic: se	q id no:2	1/25/2011	YP		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
east (all databases): text & inventor search, see search history	1/25/2011	ΥP	
stic: seq id no:2, see SCORE	1/25/2011	ΥP	
PALM: inventor search	1/25/2011	ΥP	